

<b>Notice of References Cited</b>	Application/Control No. 10/733,721		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Evan Pert		Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,773,329 A	06-1998	Kuo, Yue	438/162
*	B	US-5,817,548 A	10-1998	Noguchi et al.	438/160
*	C	US-2004/0253797 A1	12-2004	Huang et al.	438/486
*	D	US-2004/0147139 A1	07-2004	Jiang, Yeu-Long	438/795
*	E	US-5,872,889 A	02-1999	Kaltenbrunner et al.	392/418
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 840 359 A2	05-1998	EPO	Ghezze et al.	H01L 21/00
	O	JP 2000-68513A	03-2000	Japan	Sanyo	H01L 29/786
	P	JP 63-47980	02-1998	Japan	Hiranaka et al.	H01L 29/78
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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